

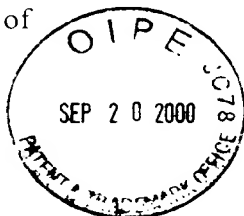
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re PATENT APPLICATION of

UEMURA et al.

Appln. No.: 08/866,129

Filed: May 30, 1997



Group: 2814

Examiner: D. Willie

Title: DEVICES RELATED TO ELECTRODE PADS FOR P-TYPE GROUP III NITRIDE COMPOUND SEMICONDUCTORS

Date: September 20, 2000

FILING OF SUPPLEMENTAL DECLARATION

Hon. Commissioner of Patents
and Trademarks
Washington, DC 20231

Sir:

Please accept the Supplemental Declaration, which is attached hereto for the above-identified application.

Respectfully submitted,

PILLSBURY MADISON & SUTRO LLP

Amelia. Cotton 30,368

By: _____

Atty: Peter W. Gowdey

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PWG/VPH:ksh
Attachment

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For: DEVICES RELATED TO ELECTRODE PADS FOR P-TYPE GROUP III NITRIDE
COMPOUND SEMICONDUCTORS



* * * * *

DECLARATION UNDER 37 C.F.R. § 1.132

Hon. Commissioner of Patents
and Trademarks
Washington, D.C. 20231

Sir:

We, Toshiya UEMURA, Naoki SHIBATA, Shizuyo NOIRI, and Shigemi
HORIUCHI, hereby declare that:

1. We are the named and true inventors of the above-captioned patent application, we are co-inventors of the subject matter disclosed and claimed in the patent application, and we are the only inventors thereof.
2. We have reviewed and are familiar with the claims and disclosure of the patent application.
3. We have reviewed and are familiar with the Office Action of April 11, 2000 and Advisory Action of May 5, 2000.
4. We have reviewed the accuracy of the experimental data and clarifying information set forth in the graphs attached hereto. The experimental data set forth in the attached graphs A-1, A-2L, A-2S, A-3, A-4 and A-5 was collected based on experiments

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UEMURA et al - Appln. No. 08/866,129

performed by us or performed under our supervision. The heat treatment of the samples was conducted at a temperature of 570°C for three (3) minutes. The experimental data set forth in the attached graphs are identical to that previously submitted. The attached graphs have been have been submitted for the purpose of including clarifying information on the x-axes to better characterize the inversion process of Au and Ni layers during heat treatment in an oxidative environment, and non-inversion of Ni and Au when during heat treatment in a non-oxidative environment. This information was requested by the Examiner in the April 11, 2000 final Office Action

5. We further declare that all statements made of our knowledge are true, and that all statements were made with the knowledge that willful false statements and the like so made are punishable by fine and/or imprisonment under Section 1001 of Title 18 of the United States Code, and may jeopardize the validity of the application or any patent issuing therefrom.

Toshiya Uemura
Toshiya UEMURA

31/08/2000
Date

Naoki Shibata
Naoki SHIBATA

31/08/2000
Date

Shizuyo Noiri
Sizuyo NOIRI

01/09/2000
Date

Shigemi Horinuchi
Shigemi HORIUCHI

31/08/2000
Date